

Notice of References Cited	Application/Control No. 10/550,610	Applicant(s)/Patent Under Reexamination SPAANS ET AL.	
	Examiner John Freeman	Art Unit 4174	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,362,775 A	12-1982	Yabe et al.	428/213
*	B	US-5,093,208 A	03-1992	Heyes et al.	428/623
*	C	US-5,384,354 A	01-1995	Hasegawa et al.	524/539
*	D	US-5,585,177 A	12-1996	Okamura et al.	428/341
*	E	US-5,618,621 A	04-1997	Hasegawa et al.	428/343
*	F	US-5,780,158 A	07-1998	Asai et al.	428/412
*	G	US-6,025,056 A	02-2000	Machii et al.	428/204
*	H	US-2001/0055690 A1	12-2001	IWASHITA et al.	428/458
*	I	US-2003/0031859 A1	02-2003	Sinsel et al.	428/332
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2006150606 A	06-2006	Japan	AOKI et al.	
	O	JP 2006181753 A	07-2006	Japan	NOGUCHI et al.	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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